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Peter Y. Yu and Manuel Cardona



TEMPERATURE COEFFICIENT OF THE REFRACTIVE INDEX OF DIAMOND- AND ZINCBLENDE-TYPE SEMICONDUCTORS

Peter Y. Yu and Manuel Cardona<sup>+</sup>

Brown University, Providence, Rhode Island, USA

and

Deutsches Elektronen-Synchrotron DESY, Hamburg, Germany

+ J.S. Guggenheim Memorial Foundation Fellow

### Abstract

We have calculated the temperature coefficient of the long-wavelength refractive index of several group IV and III-V semiconductors using the Penn model for the electronic contribution to the dielectric constant. The isotropic band gap of this model is identified with the band gap at the X point of the Brillouin zone, which can be simply expressed in terms of pseudopotential coefficients. The explicit temperature dependence of this gap is calculated by applying to these pseudopotential coefficients the appropriate Debye-Waller factors. The thermal expansion effect is obtained in the manner suggested recently by Van Vechten. Good agreement between the calculated and the observed temperature dependence of the long-wavelength refractive index is found.

## 1. Introduction

Recently Phillips' theory of ionicity has been applied successfully to calculate various properties, namely ionization potential<sup>2</sup>, cohesive energy<sup>3</sup>, non-linear optical susceptibilities<sup>4</sup>,<sup>5</sup>,<sup>6</sup> etc., of a large number of covalent and ionic compounds. At the heart of this theory is a very simple isotropic one-gap model of the band structure due to Penn<sup>7</sup>. Heine and Jones<sup>8</sup> pointed out that one reason why such a simple model works for the diamond-type semiconductors is that the gap on the surface of the Jones-zone is nearly constant over a large area. By identifying the "Penn gap" with the band gap at the center of the (110) Jones-zone face, they calculated the hydrostatic pressure coefficient of the dielectric constant of Si and Ge. In this paper we generalise Heine and Jones' calculation to the III-V semiconductors and obtain the "Penn gap" as a function of the pseudopotential coefficients. We then calculate with this model the temperature coefficient of the refractive index of several group IV and group III-V semiconductors.

#### 2. Penn Model

The electronic centribution to the long-wavelength dielectric constant of a solid in the Penn model is given by:<sup>7,9</sup>

$$\varepsilon(\mathbf{o}) \simeq 1 + \mathbf{D} \frac{\omega_{\mathbf{p}}^{2}}{\omega_{\mathbf{g}}^{2}}$$
(1)

where  $\omega_p$  is the plasma frequency of the valence electrons,  $\omega_g$  the "Penn gap", and D is a parameter introduced by Van Vechten<sup>9</sup> to take into account the effect of d-like core electrons. It is difficult to speculate on how D will vary with temperature and volume. Since D is of the order of unity and its variations are not expected to be large we shall neglect this factor in our calculation..

By differentiation of Eq. (1) with respect to temperature (throughout this paper pressure is assumed to be constant when the d-sign of differentiation is used) we obtain:

$$\frac{1}{\varepsilon} \frac{d\varepsilon}{dT} = \frac{\varepsilon - 1}{\varepsilon} \left( \frac{1}{\omega^2} \frac{d\omega_p^2}{dT} - 2 \left( \frac{1}{\omega_g} \frac{d\omega_g}{dT} \right) \right)$$
$$= \frac{\varepsilon - 1}{\varepsilon} \left( -3\alpha - 2 \left( \frac{1}{\omega_g} \frac{d\omega_g}{dT} \right) \right)$$
(2)

where  $\alpha$  = coefficient of linear expansion. In Eq. (2) we have made use of the known proportionality of  $\omega_p^2$  to the valence electron concentration. We decompose the temperature coefficient of  $\omega_g$  which appears in Eq. (2) into its "explicit" temperature dependence at constant volume and its volume expansion effect:

$$\frac{1}{\omega_{g}} \frac{d\omega_{g}}{dT} = \frac{1}{\omega_{g}} \left(\frac{\partial\omega_{g}}{\partial T}\right) + 3\alpha \frac{V}{\omega_{g}} \left(\frac{\partial\omega_{g}}{\partial V}\right)_{T}$$
(3)

# 3. Explicit Temperature Dependence of the Penn Gap

Following Heine and Jones<sup>8</sup> we identify the "Penn gap"  $\omega_g$  with the gap at the X point of the Brillouin zone. As is well known, its energy is close to that of the strongest peak in the oscillator strength and the reflectivity of the group IV and group III-V semiconductors<sup>10</sup>. An expression for this gap as a function of the pseudopotential form factors v(111), and v(220) has been calculated by Heine and Jones<sup>8</sup> for germaniumtype materials using perturbation theory. This expression can be easily generalized to zincblende-type compounds. We find, in Rydbergs<sup>11</sup>

(4)

$$\omega_{g}^{\pm} = 2v_{s}(220) \pm 2v_{a}(200) + \frac{2(v_{s}(111) \pm v_{a}(111))^{2}}{(\frac{2\pi}{a})^{2}}$$

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where a is the lattice constant in Bohr radii. The subscript s and a of the pseudopotential coefficients v (220), v (200) and v(111) denotes their symmetric and antisymmetric components respectively. The antisymmetric coefficients  $v_a(200)$  and  $v_a(111)$  are responsible for the splitting of the  $X_1$  conduction bands (± sign in Eq. (4)) but does not change, to first order, the average value of  $\omega_g$ . Since the splitting is known to be small for III-V compounds, it can be neglected for the purpose of calculating dielectric properties.

We thus obtain

$$\omega_{g} = 2 \left( v_{g}(220) + \frac{(v_{g}(111))^{2} + (v_{a}(111))^{2}}{(\frac{2\pi}{a})^{2}} \right)$$
(5)

The values of the pseudopotential coefficients  $v_g(220)$ ,  $v_g(111)$  and  $v_a(111)$  for several group IV and group III-V semiconductors are listed in Table I together with other parameters relevant for our calculations. The values of  $\omega_g$  obtained from these parameters with Eq. (5) are listed in Table II, together with the values obtained from the dielectric constant (see Eq. (1)) by Van Vechten<sup>9</sup> and the energy  $E_2$  of the corresponding reflectivity peak. The good agreement between these three sets of values confirms the validity of Eq. (5).

Equation (5) can be used to calculate the temperature dependence of  $\omega_g$  by multiplying the Fourier component of the pseudopotential v(g) by the appropriate Debye-Waller factor<sup>12</sup>,<sup>13</sup>:

$$e^{-B(T)} |g|^2 = e^{-\frac{|g|^2}{6} \langle u^2 \rangle}$$
 (for cubic crystals) (6)

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For a crystal with r atoms per unit cell the average square displacement of atom K is<sup>14</sup>:

$$\langle u^{2}_{K} \rangle = \frac{1}{2NM_{K}} \sum_{\substack{g,j \\ g,j}} |\underline{e}(K,j,\underline{q})|^{2} \qquad \frac{\coth \frac{1}{2} \beta \omega_{j}(\underline{q})}{\omega_{j}(\underline{q})}$$
(7)

where  $\beta = kT$ .  $M_{K}$  is the mass of the K-th atom, N the number of unit cells per unit volume,  $\omega_{j}(q)$  is the frequency of the normal mode with wavevector q in the j th-branch and e(K, j, q) the polarization vector of the corresponding displacement of atom K.

In group IV semiconductors the two atoms of the unit cell are identical and Eq. (7) simplifies to:

$$\langle u^2 \rangle = \frac{1}{2NM} \sum_{\substack{\underline{q},j}} \frac{\coth \frac{1}{2} \beta \omega_j(\underline{q})}{2 \omega_j(\underline{q})}$$
(8)

we calculate  $\frac{\partial B(T)}{\partial T}$  with the Debye model for the phonon spectrum and obtain with Eq. (8):

$$\frac{\partial B(T)}{\partial T} = \frac{3}{2} \frac{1}{MkT^2} F\left(\frac{H}{T}\right), \qquad (9)$$

with

$$F(x) = \frac{1}{x^2} \left( \frac{2}{x} \int_{0}^{x} \frac{y \, dy}{e^y - 1} - \frac{x}{e^x - 1} \right)$$
(10)

We shall use in our calculation values of the Debye temperature  $(H)_D$  at room temperature, since most experimental data are obtained around room temperature. The function F(x) has been evaluated by Benson and Gill<sup>15</sup>.

For the III-V compounds it is no longer possible to relate  $\langle u^2 \rangle$  directly to the phonon spectrum with Eq. (7) since the masses of the two constituent atoms are not equal. However for those of the III-V compounds we are considering we find that the ratio of the heavier mass to the lighter is smaller than two. In the case of the alkali halides it was found that at room temperature the average square displacements for the anion and cation differ by less than 10 % even for masses which differ by a factor of  $3.^{16}$  Hence we assume for the sake of simplicity that  $\langle u^2_{III} \rangle = \langle u^2_V \rangle$ . The validity of this assumption cannot be checked until the Debye-Waller factors for the III-V compounds have been determined. However the results of our calculation seem to support this assumption. Thus for the III-V compounds we use the formula:

$$\frac{\partial B_{III}}{\partial T} = \frac{\partial B_{V}}{\partial T} \simeq \frac{\partial \overline{B}}{\partial T} = \frac{3}{kT^{2}} \frac{3}{(M_{III} + M_{V})} F \left(\frac{H_{D}}{T}\right)$$
(11)

combining Eqs. (5) and (6) we obtain:

$$\frac{\partial \omega_{g}}{\partial T} = 2 \left[ v_{g}(220) \left( - | \underline{g}(220)|^{2} \frac{\partial \overline{B}}{\partial T} \right) + \frac{\left( v_{g}(111) \right)^{2} + \left( v_{a}(111) \right)^{2}}{\left( \frac{2\pi}{a} \right)^{2}} \left( - 2 | \underline{g}(111) |^{2} \frac{\partial \overline{B}}{\partial T} \right) \right]$$

$$(12)$$

In order to simplify the evaluation of Eq. (12) we note that for the semiconductors we are considering v(220) is small and  $|g(220)|^2 \ge 2|g(111)|^2$ . Equation (12) can thus be approximated by the expression:

$$\frac{1}{\omega_{g}} \left( \frac{\partial \omega_{g}}{\partial T} \right)_{V} \simeq -2 \left| g(111) \right|^{2} \frac{\partial \overline{B}}{\partial T}$$
(13)

with an error smaller than 10 %.

## 4. Volume Dependence of the "Penn gap"

The volume coefficient of  $\omega_g$  can be calculated with Eq. (5) and the known derivatives of  $\mathbf{v}(\mathbf{q})$  with respect to  $|\mathbf{q}|$ .<sup>8</sup> Since this volume dependence is only responsible for less than 20 % of the total calculated temperature dependence of  $\omega_g$ , we choose for its evaluation the simpler, although possibly less accurate procedure given by Van Vechten<sup>9</sup>.

We start with the equation:

$$\omega_{\rm g} = (\omega_{\rm h}^2 + C^2)^{1/2} \tag{14}$$

where  $\omega_h$  is the homopolar energy gap of the material, and C the heteropolar energy gap. In order to calculate the volume dependence of  $\omega_g$  it is necessary to know the corresponding dependence of  $\omega_h \{\omega_h \propto a^{-2.48}\}^9$ and C. As suggested by the value of  $(\frac{\partial C}{\partial V})_T$  for the alkali halides<sup>9</sup>, we take  $(\frac{\partial C}{\partial V})_T \simeq 0$ . Our result does not depend critically on this assumption since C only accounts for a small fraction of  $\omega_g$ , whose volume dependence, in turn, only accounts for a small fraction of the total temperature dependence of  $\omega_g$ . We thus find:

$$\frac{\mathbf{v}}{\omega_{g}} \left(\frac{\partial \omega_{g}}{\partial \mathbf{V}}\right)_{T} \cong -0.8 \times \frac{\omega_{h}^{2}}{\omega_{g}^{2}}$$
(15)

## 5. Temperature Dependence of the long-wavelength Refractive Index

We have listed in Table I the parameters used for our calculation of  $\frac{1}{n} \left(\frac{\partial n}{\partial T}\right)_P$ based on Eqs. (2), (3), (13), and (15). We have used for the Debye temperature the values obtained from specific heat measurements. Batterman and Chipman<sup>17</sup> found that the Debye temperatures obtained for Ge and Si from x-ray intensity measurements were about 20 % lower than those from specific heat. This fact introduces an uncertainty of about 40 % in our calculation of  $\frac{1}{\omega_g} \left(\frac{\partial \omega_g}{\partial T}\right)_V$ . We believe this uncertainty is our main source of error.

In Table II we show the temperature coefficient  $\frac{d_{\omega g}}{dT}$  calculated with Eqs.(13) and (15) and those determined experimentally for E<sub>2</sub>. The agreement is satisfactory.

In Table III we show the calculated value of  $\frac{1}{n} \frac{dn}{dT}$  at 300° K compared with experimental results. Theoretical I are the values obtained by using in Eq. (2) the calculated coefficients  $\frac{1}{\omega_g} \frac{d\omega_g}{dT}$  while Theoretical II are the values obtained by using the experimental  $\frac{1}{E_2} \frac{dE_2}{dT}$  and assuming  $\frac{1}{\omega_g} \frac{d\omega_g}{dT} = \frac{1}{E_2} \frac{dE_2}{dT}$ . We note that the trend in the experimental values in going from one material to another is better represented by Theoretical I than by Theoretical II. A possible explanation is that the values of  $\frac{dE_2}{dT}$  determined by the wavelength modulation technique are sensitive to the detailed critical point structures while  $\omega_g$  represents the somewhat different average gap. The agreement between the calcualted values of  $\frac{1}{n} \frac{dn}{dT}$  and the experimental values is always better than 40 Z, which is the error of our calculation due to uncertainties in the Debye temperature.

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#### Table I

The various parameters used in this article for calculating the temperature dependence of the long wavelength refractive index of group IV and III-V semiconductors.

	<sup>l</sup> Pseudopotential <u>Coeff.(Ryd)</u>		ε(o) <sup>.</sup>	Coeff. of linear Expansion at	Debye Temp. (H) <sub>D</sub> at	Lattice Constant (in Bohr radii)	
· · · · · · · · · · · · · · · · · · ·	v <sub>s</sub> (220)	v <sub>s</sub> (111)	v <sub>a</sub> (111)	(b)	room temperature	З00° К	(b)
С	-0.022	-0.514	-	5.7	c 1.1x10 <sup>-6</sup> / <sup>0</sup> K	<sup>g</sup> 1880 <sup>о</sup> к	6.74
	+0.337	-0.811			•	h	
Si	+0.04	-0.21	-	12.0	$2.5 \times 10^{-6}$	647	10.26
Ge	+0.01	-0.23	-	16.0	d 5.7x10 <sup>-6</sup>	h 354	10.69
GaAs	+0.01	-0.23	+0.07	10.9	d 5.7x10 <sup>-6</sup>	d 360	10.68
GaSb	0.0	-0.22	+0.06	14.4	<sup>d</sup> 6.3x10 <sup>-6</sup>	<sup>d</sup> 230	11.56
InAs	0.0	-0.22	+0.08	12.3	<sup>e</sup> 5.4x10 <sup>-6</sup>	d 270	11.41
InSb	0.0	-0.20	+0.06	15.7	d 5.1x10 <sup>-6</sup>	d 150	12.24
InP	+0.01	-0.23	+0.07	9.6	e 4.9x10 <sup>-6</sup>	đ 420	11.09
GaP	+0.03	-0.22	+0.12	9.1	<sup>f</sup> 5.81x10 <sup>-6</sup> <sup>e</sup> 5.3x10 <sup>-6</sup>	<sup>i</sup> 470	11.03

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   Debye temperature (446° K) calculated from the elastic constants (E.F. Steigmeier, Appl.Phys. Letters 3, 6 (1963))-

#### Table II

Calculated and experimental values of the "Penn gap"  $\omega_g$ , energy  $E_2$  of the highest peak in the reflection spectrum, and temperature coefficient of  $\omega_g$  (theoretical) and  $E_2$  (experimental).

ι	g(theoretical)	$\omega_{g}$ (experimental)	Highest Peak	$d\omega_{g(x-1x)}$	dE <sub>2</sub>
from Eq. (5)		from Eq. (1)	in Reflection Spectrum	dT calc).	$\frac{dT}{dT}$ (exp.)
	in eV	in eV	(E <sub>2</sub> ) in eV	In ev/sk	III ev/- K
С	7.8 29.6	13.6	a 12.6	-1.17x10 <sup>-4</sup> -4.6x10 <sup>-4</sup>	
Si	4.2	4.8	ъ 4.44	-1.9x10 <sup>-4</sup>	b -2.2x10 <sup>-4</sup> d +0.5x10 <sup>-4</sup>
Ge	4.4	. 4.3 .	b 4.49	-3.3x10 <sup>-4</sup>	$b -2.4 \times 10^{-4}$ $d -2 \times 10^{-4}$
GaAs	<b>s 4.</b> 9 ·	5.2	b 5.11	-3.5x10 <sup>-4</sup>	$b -3.6 \times 10^{-4}$ f -3.3 \times 10^{-4}
GaSt	o 4 <b>.</b> 8	4.1	b 4.35	-4.7x10 <sup>-4</sup>	$b = -4.1 \times 10^{-4}$ e = -6.2 x 10 <sup>-4</sup>
InAs	s 4.9	4.58	b 4.74	$-3.8 \times 10^{-4}$	<sup>b</sup> -5.6x10 <sup>-1</sup>
InSt	o 4.5 .	3.74	ь 4.23	-6.9x10 <sup>-1</sup>	<sup>b</sup> -3.6x10 <sup>-4</sup>
InP	5.2	5.2	c 5.0	-2.3x10 <sup>-1</sup>	
GaP	5,85	5.75	<sup>-с</sup> 5.3	$-1.9 \times 10^{-4}$	f -4.5x10 <sup>-4</sup>

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Table III

Temperature coefficient of long wavelength refractive index of group IV and III-V semiconductors.

	$\frac{1}{n}$ $\frac{dn}{dT}$ (Theoretical I)	$\frac{1}{n} \frac{dn}{dT}$ (Theoretical II)	$\frac{1}{n}$ $\frac{dn}{dT}$ (Experimental)
C	1.1x10 <sup>-5</sup> /° K	· · · · · · · · · · · · · · · · · · ·	a 0.5x10 <sup>-5</sup> / <sup>0</sup> K
Si	3.7x10 <sup>-5</sup>	4.2x10 <sup>-5</sup> / <sup>o</sup> K	ь 3.9x10 <sup>-5</sup> /°к
Ge	6.1x10 <sup>-5</sup>	4.2x10 <sup>-5</sup>	b 6.9x10 <sup>-5</sup>
GaAs	$5.4 \times 10^{-5}$	$5.7 \times 10^{-5}$	c 4.5x10 <sup>-5</sup>
GaSb	9.3x10 <sup>-5</sup>	5.1x10 8.0x10 <sup>-5</sup> 12.4 x 10 <sup>-5</sup>	c 8.2x10 <sup>-5</sup>
InAs	$6.7 \times 10^{-5}$	10.3x10 <sup>-5</sup>	
InSb	15.0x10 <sup>-5</sup>	7.4x10 <sup>-5</sup> 11.9x10 <sup>-5</sup>	c 11.9x10 <sup>-5</sup>
InP	3.6x10 <sup>-5</sup>		c 2.7x10 <sup>-5</sup>
GaP	$2.2 \times 10^{-5}$	6.8x10 <sup>-5</sup>	d 3.7×10 <sup>-5</sup>

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